Search Notes			

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/716,980	CHAN ET AL.	
Examiner	Art Unit	
John R. Hardee	1751	

	SEARCHED		
Class	Subclass	Date	Examiner
149	19.1	 5/3/2004	JRH
	19.2		
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	19.8		
	19.9	1	
	19,91	1	
To date		6/10/04	V

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
AS	elfor	JC 1 400	FRES.

SEARCH I	SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR	
EAST text and image	5/3/2004	JRH	